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Ruth Montalvo / Ruth Montalvo Date: 05/20/05

Customer No. 026418

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney's Docket No.: GK-ZEI-3274/500343.20294

U.S. Application No.:

International Application No.: PCT/EP2003/012673

International Filing Date: NOVEMBER 13, 2003

13 NOVEMBER 2003

Priority Date Claimed: NOVEMBER 21, 2002

21 NOVEMBER 2002

Title of Invention: OPHTHALMOLOGICAL APPLIANCE COMPRISING AN EYE TRACKER

Applicant(s) for (DO/EO/US): Oliver BAUMANN, Michael CLAUS, Axel DOERING,
Ingo KOSCHMIEDER, Thomas SCHULZE and Bernd SPRUCK

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INFORMATION DISCLOSURE STATEMENT

S I R:

Applicant herewith submits together with the simultaneously filed National Phase application of PCT/EP2003/012673, a copy of the International Search Report (PCT/ISA/210) dated April 27, 2004 and German Examination Report (102 54 369.0) dated September 11, 2003, citing the following references:

	Document Number	Date	Name and/or Country	English Translation
AA	5,943,118	08/24/1999	Koschmieder , et al.	
AB	6,145,990	11/14/2000	Uchida	
AC	6,220,706	04/24/2001	Foley	
AD	2002/0060778	05/23/2002	Su, et al.	
AL	WO 99/27412	06/03/1999	WIPO	
AM	WO 99/56611	11/11/1999	WIPO	
AN	1 088 511	04/04/2001	European	
AO	101 51 314	04/30/2003	Germany	Abstract only/U.S. equivalent 10/268,319
AP	1 327 412	07/16/2003	European	Abstract only/U.S. equivalent 10/501,020

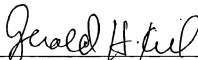
Accompanying this Information Disclosure Statement and form PTO-1449 are copies of the documents (US first pages only) including 2 English Abstracts. Documents AB, AC and AN are mentioned on pages 1 and 2 of the substitute specification.

18/535730
JC18 Rec'd PCT/US 20 MAY 2005

The USPTO waived the requirement under 37 CFR § 1.83(a)(2)(i) for submitting copies of US patents and US patent application publications in all U.S. applications filed after June 30, 2003.

This submission is not an admission that the information disclosed in the documents is material to the patentability of the invention disclosed and/or claimed in the above-identified application.

Respectfully submitted,



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Enclosures:

Search Reports (PCT/ISA/210);
German Examination Report
PTO-1449;
4 US documents (first pages)
5 Foreign documents
2 English Abstracts

LIST OF PRIOR ART CITED BY APPLICANT
(Filed on May 20, 2005)

JC20 Rec'd PCT/PTO 19 MAY 2005

Docket No. GK-ZEI-3274/500343.20294

Applicant(s): Oliver BAUMANN, Michael CLAUS, Axel DOERING, Ingo KOSCHMIEDER,
Thomas SCHULZE and Bernd SPRUCK

Application No. (Int'l Appl No. PCT/EP2003/012673 13NOV03) Group:

Filed: Examiner:

U.S. PATENT DOCUMENTS

Exam. Init		Document Number	Date	Name	Class	Sub-Class	Filing Date Appropriate
/HD/	AA	5,943,118	08/24/1999	Koschmieder, et al.			
↓	AB	6,145,990	11/14/2000	Uchida			
↓	AC	6,220,706	04/24/2001	Foley			
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	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	CLASS	Sub-Class	Translation YES	NO
/HD/	AL	WO 99/27412	06/03/1999	WIPO				
↓	AM	WO 99/56611	11/11/1999	WIPO				
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↓	AO	101 51 314	04/30/2003	Germany			Abstract only	
↓	AP	1 327 412	07/16/2003	European			Abstract only	
	AQ							
	AR							
	AS							
	AT							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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	AY	
	AZ	

Examiner: /Hung Dang/

Date: 02/12/2008

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.